# FAIRCHILD

SEMICONDUCTOR

# 74ABT241 **Octal Buffer/Line Driver with 3-STATE Outputs**

#### **General Description**

The ABT241 is an octal buffer and line driver with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus-oriented transmitter/ receiver.

## Revised November 1999

January 1995

## **Features**

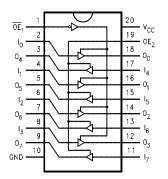
- Non-inverting buffers
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

#### **Ordering Code:**

Package Number	Package Description
M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
	M20B M20D MSA20

Device also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Connection Diagram**



#### **Pin Descriptions**

Pin Names	Description
OE <sub>1</sub>	Output Enable Input (Active LOW)
OE <sub>2</sub>	Output Enable Input (Active HIGH)
I <sub>0</sub> —I <sub>7</sub>	Inputs
O <sub>0</sub> -O <sub>7</sub>	Outputs

#### **Truth Table**

OE <sub>1</sub>	I <sub>0-3</sub>	0 <sub>0-3</sub>	OE <sub>2</sub>	I <sub>4-7</sub>	0 <sub>4-7</sub>
Н	х	Z	L	Х	Z
L	н	н	н	н	н
L	L	L	н	L	L

H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial Z = High Impedance

#### Absolute Maximum Ratings(Note 1)

Storage Temperature	$-65^{\circ}C$ to $+150^{\circ}C$
Ambient Temperature under Bias	$-55^{\circ}C$ to $+125^{\circ}C$
Junction Temperature under Bias	$-55^{\circ}C$ to $+150^{\circ}C$
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disabled or	
Power-Off State	-0.5V to 5.5V
in the HIGH State	-0.5V to V <sub>CC</sub>
Current Applied to Output	
in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
DC Latchup Source Current	
(Over Comm Operating Range)	–500 mA
Over Voltage Latchup (I/O)	10V

# Recommended Operating Conditions

Free Air Ambient Temperature	$-40^{\circ}C$ to $+85^{\circ}C$
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Data Input	50 mV/ns
Enable Input	20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

### **DC Electrical Characteristics**

Symbol	Parame	eter	Min	Тур	Max	Units	V <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Vol	tage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage		2.5			V	Min	I <sub>OH</sub> = -3 mA
			2.0			V	Min	I <sub>OH</sub> = -32 mA
V <sub>OL</sub>	Output LOW Voltage				0.55	V	Min	I <sub>OL</sub> = 64 mA
IIH	Input HIGH Current				1 1	μΑ	Max	V <sub>IN</sub> = 2.7V (Note 4) V <sub>IN</sub> = V <sub>CC</sub>
I <sub>BVI</sub>	Input HIGH Current Bre	eakdown Test			7	μA	Max	$V_{IN} = 7.0V$
	Input LOW Current				-1	μι	max	V <sub>IN</sub> = 0.5V (Note 4)
١L					-1	μΑ	Max	$V_{IN} = 0.0V$ (Note 4)
V <sub>ID</sub>	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \ \mu A$ All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Curren	nt			10	μA	0-5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Curren	nt			-10	μΑ	0-5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
I <sub>OS</sub>	Output Short-Circuit Cu	urrent	-100		-275	mA	Max	$V_{OUT} = 0.0V$
I <sub>CEX</sub>	Output High Leakage 0	Current			50	μΑ	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test				100	μΑ	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Current				50	μΑ	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current				30	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current				50	μΑ	Max	$\overline{OE}_n = V_{CC};$
								All Others at $\mathrm{V}_{\mathrm{CC}}$ or Ground
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled			2.5	mA		$V_I = V_{CC} - 2.1V$
		Outputs 3-STATE			2.5	mA	Max	Enable Input $V_I = V_{CC} - 2.1V$
		Outputs 3-STATE			50	μΑ		Data Input $V_I = V_{CC} - 2.1V$
								All Others at $\mathrm{V}_{\mathrm{CC}}$ or Ground
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	No Load				mA/	Max	Outputs Open
	(Note 4)				0.1	MHz	wax	OE <sub>n</sub> = GND, (Note 3)
								One Bit Toggling, 50%
								Duty Cycle

Note 3: For 8 bits toggling,  $I_{CCD} < 0.8 \mbox{ mA/MHz}.$ 

Note 4: Guaranteed, but not tested.

## **DC Electrical Characteristics**

(SOIC pac	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions $C_L = 50 \text{ pF},$ $R_L = 500\Omega$
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.5	0.8	V	5.0	T <sub>A</sub> = 25°C (Note 5)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.3	-0.8		V	5.0	$T_A = 25^{\circ}C$ (Note 5)
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	2.7	3.1		V	5.0	$T_A = 25^{\circ}C$ (Note 7)
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	2.0	1.5		V	5.0	$T_A = 25^{\circ}C$ (Note 6)
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		1.1	0.8	V	5.0	T <sub>A</sub> = 25°C (Note 6)

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	Note 5: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.
	Note 6: Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V <sub>ILD</sub> ), 0V to threshold (V <sub>IHD</sub> ).
I	Guaranteed, but not tested.

Note 7: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

#### **AC Electrical Characteristics**

(SOIC and SSOP package)

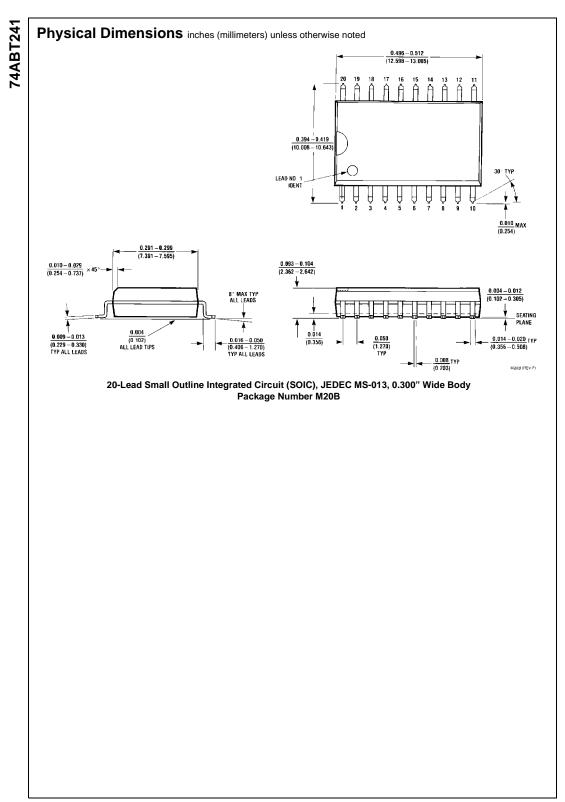
Symbol	Parameter	$T_{A} = +25 ^{\circ}\text{C}$ $V_{CC} = +5\text{V}$ $C_{L} = 50 \text{pF}$			$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.0		4.6	1.0	4.6	50
t <sub>PHL</sub>	Data to Outputs	1.0		4.6	1.0	4.6	ns
t <sub>PZH</sub>	Output Enable	1.1		6.8	1.1	6.8	50
t <sub>PZL</sub>	Time	1.3		6.8	1.3	6.8	ns
t <sub>PHZ</sub>	Output Disable	1.6		6.8	1.6	6.8	
t <sub>PLZ</sub>	Time	1.0		5.9	1.0	5.9	ns

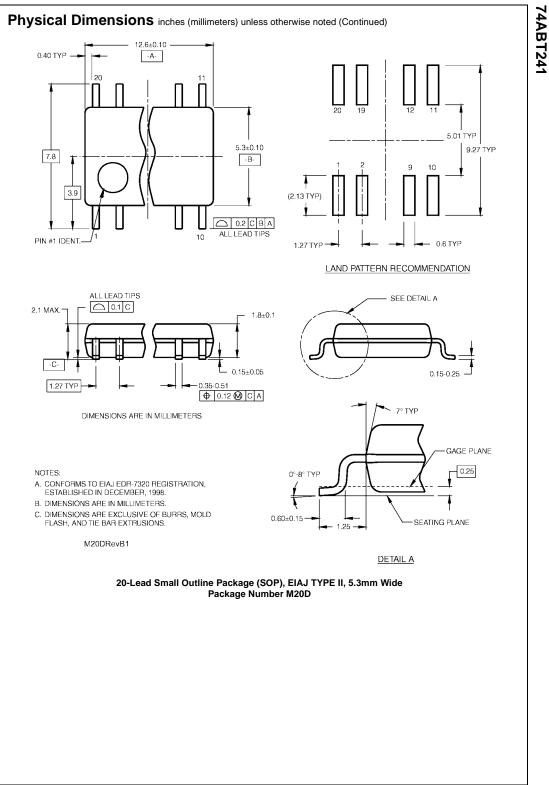
## Capacitance

Symbol	Parameter	Тур	Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5.0	pF	$V_{CC} = 0V$
C <sub>OUT</sub> (Note 8)	Output Capacitance	9.0	pF	$V_{CC} = 5.0V$

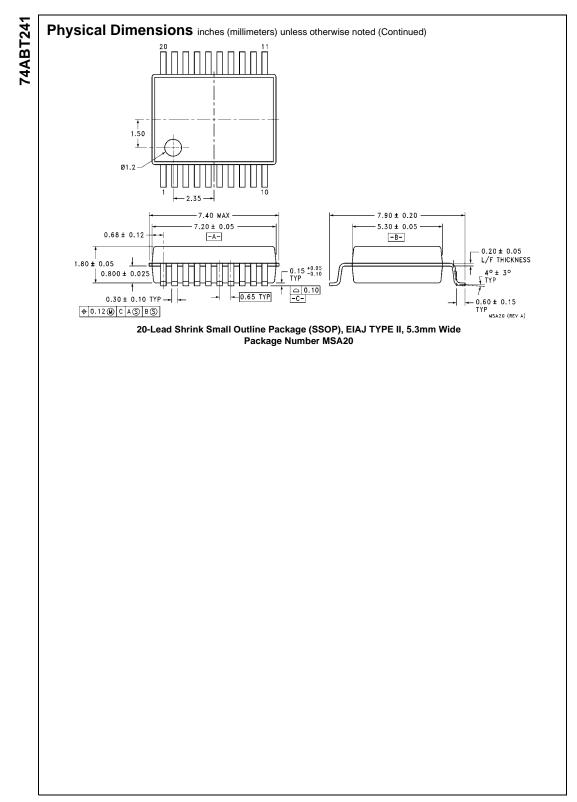
Note 8:  $C_{OUT}$  is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.

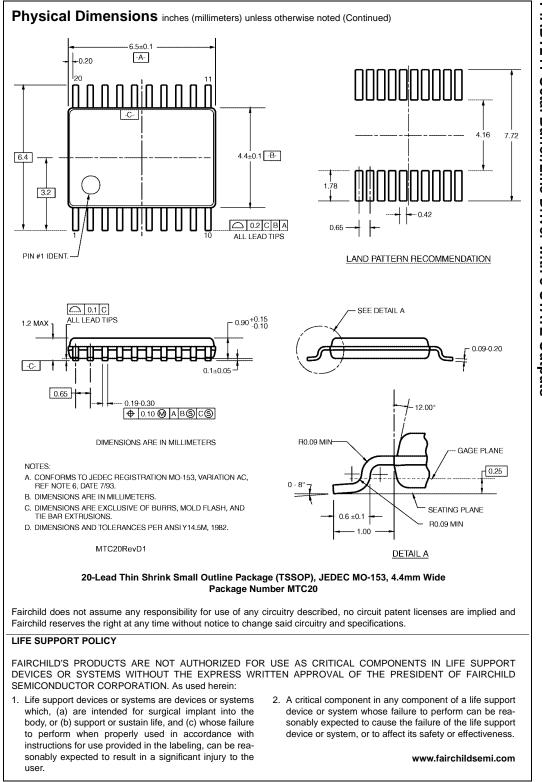
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